Se	arch No	otes	

Application/Control No.	Applicant(s)/Patent ur Reexamination	ider
10/535,452	OGAWA ET AL.	
Examiner	Art Unit	•
Duy Vu N. Deo	1765	

SEARCHED			
Class	Subclass	Date	Examiner
	, 		
	•		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		-	
	l		

SEARCH NOT (INCLUDING SEARCH	'ES STRATEGY)
	DATE	EXMR
east: key words, class/sub (438/717)	8/22/2007	D∨D
*		